

301/1152-4

Microprocessor Laboratory
Sixth Course on Basic VLSI Design Techniques
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A CASE STUDY

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These are preliminary lecture notes intended only for distribution to participants.

A Case Study: 4 μ W 8b Algorithmic ADC

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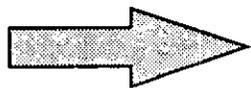
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Outline

- Design Specifications;
- The algorithmic A/D converter;
- Numerical Model and Simulation
- Digital and Analog Design (Control logic, phases generator, OTAs, switches, capacitors)
- Layout
- Test set-up & Measurements

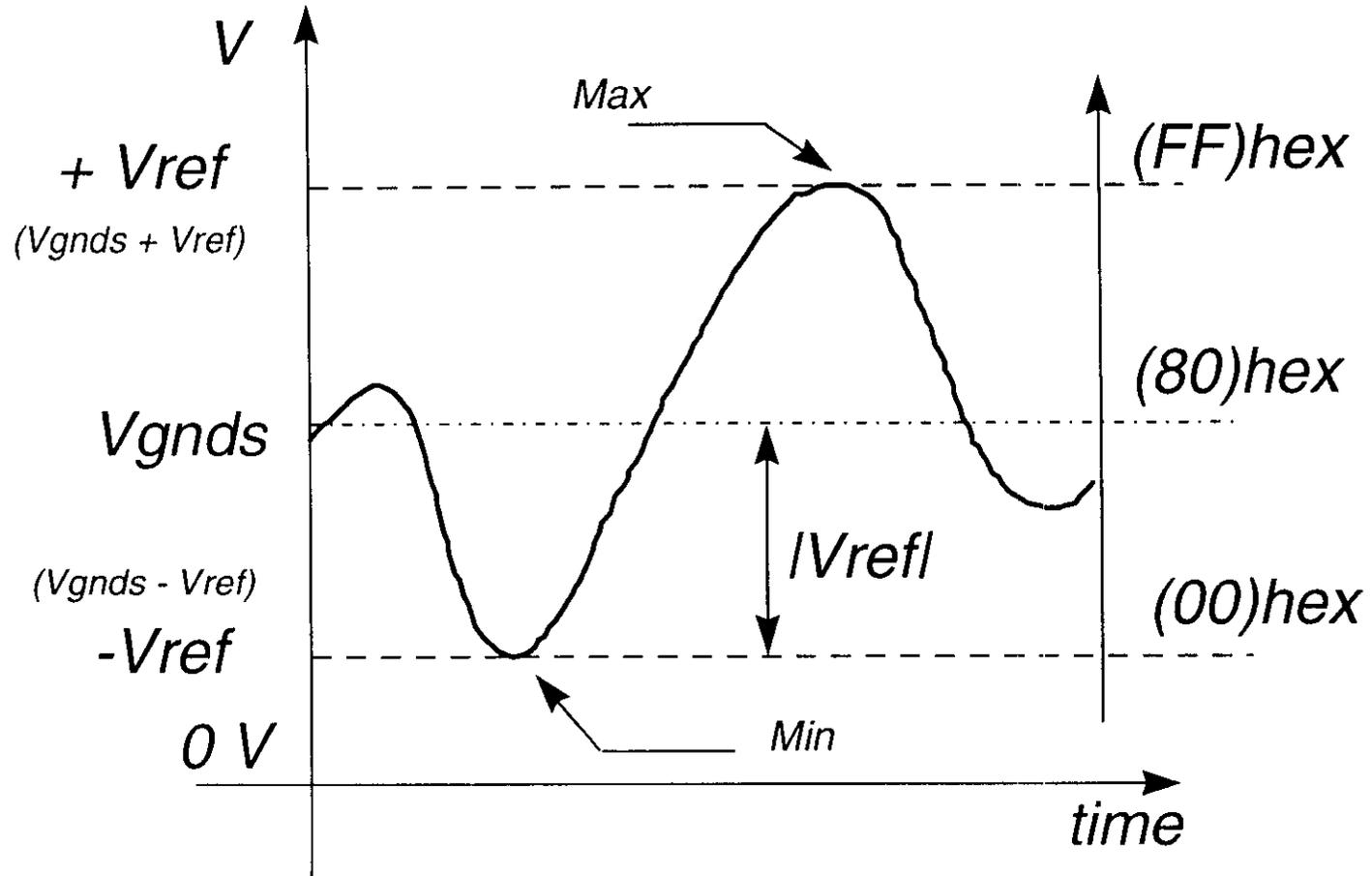
Design specifications

- Resolution: 8 bits
- Single Voltage Supply: 2V - 2.8V
- Bandwidth: 250Hz (Sample Rate Min. 500Hz)
- Bipolar input signal: $V_{gnds} \pm 400 \text{ mV}$
- Very Low Die Size
- Very Low Power Dissipation

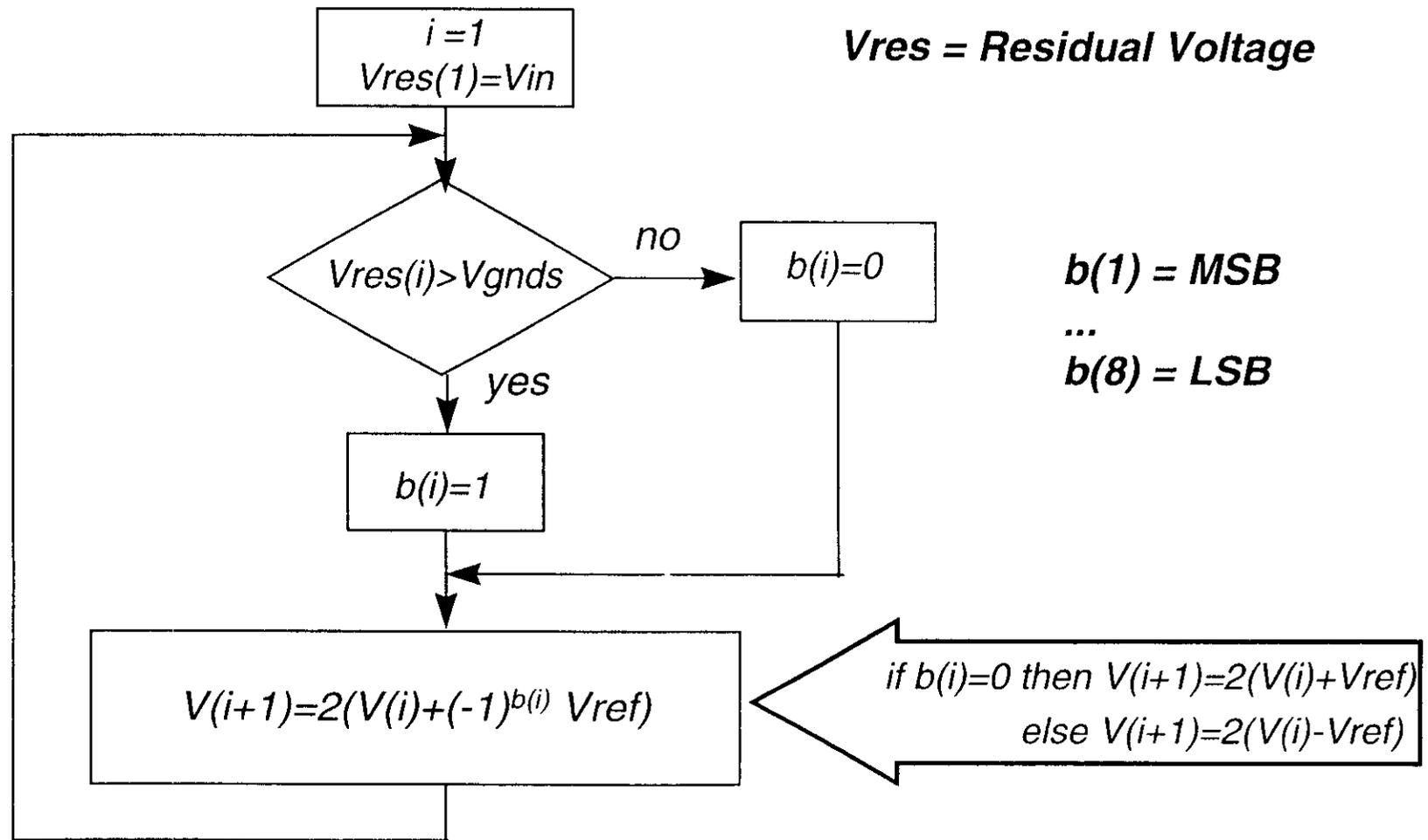


Pacemaker Application

"Bipolar" input signal



The algorithmic A/D converter



What do I need to realise an algorithmic A/D converter ?

$$V(i+1) = 2 (V(i) + (-1)^{b(i)} V_{ref})$$

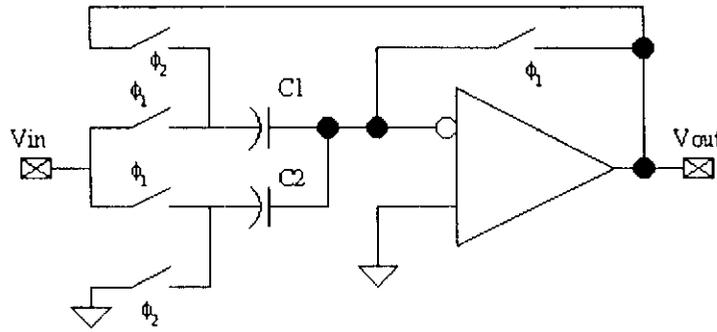
■ Multiplier x 2

■ Adder $\pm V_{ref}$

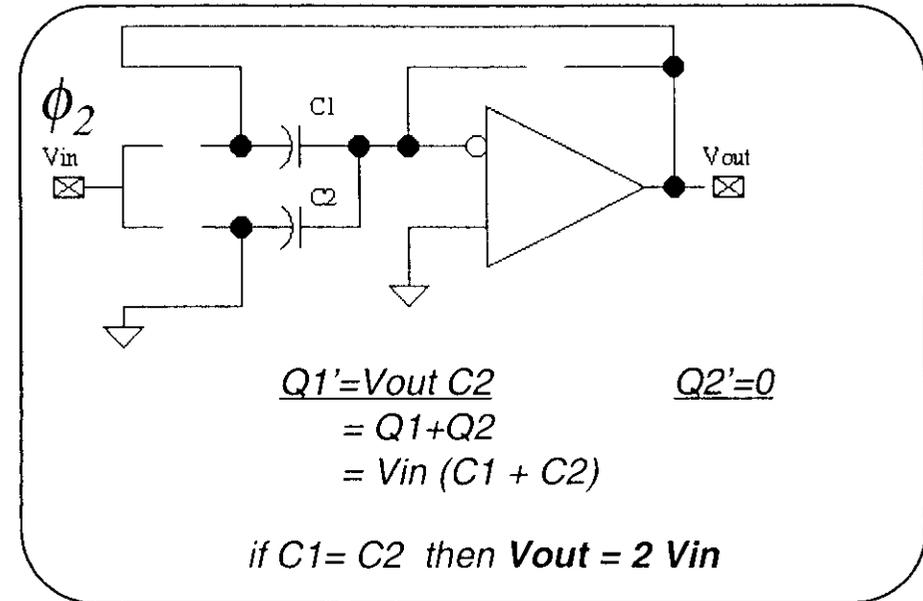
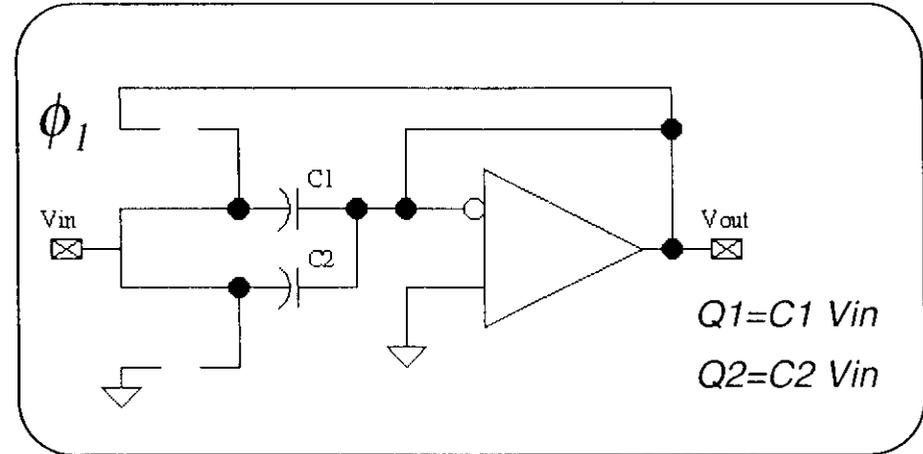
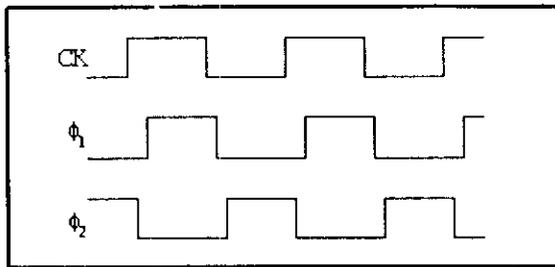
■ Comparator

if ($V_{res}(i) > V_{gnds}$) then ...

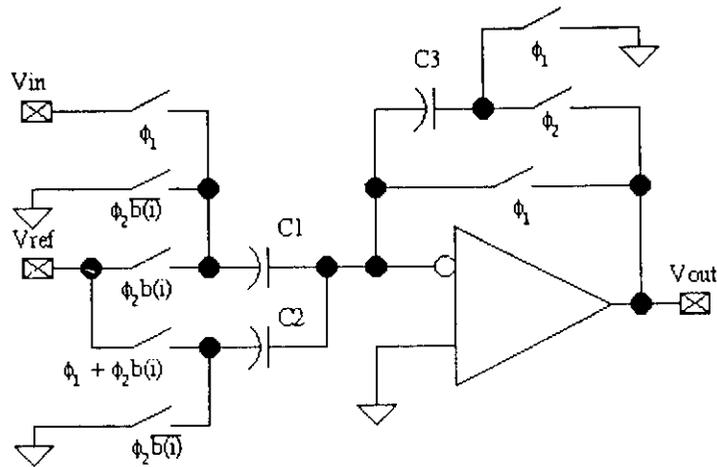
Multiplier x 2



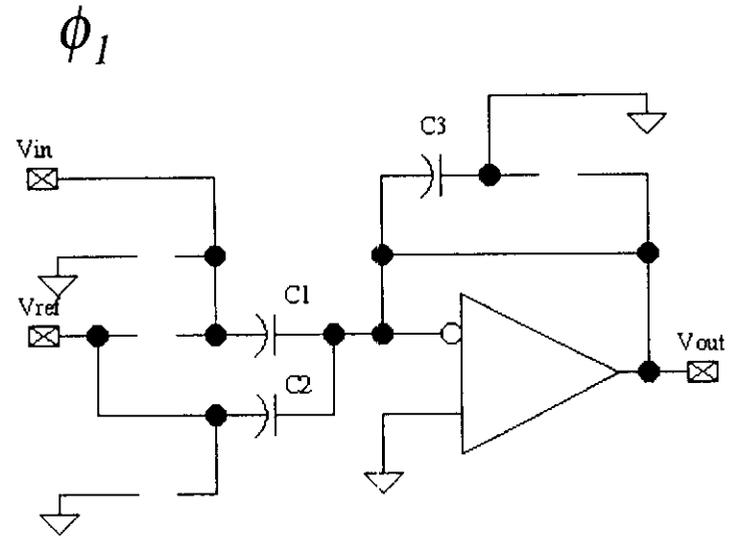
Non Overlapping phases



Adder $\pm V_{ref}$



$b(i)$ is the last output bit elaborated

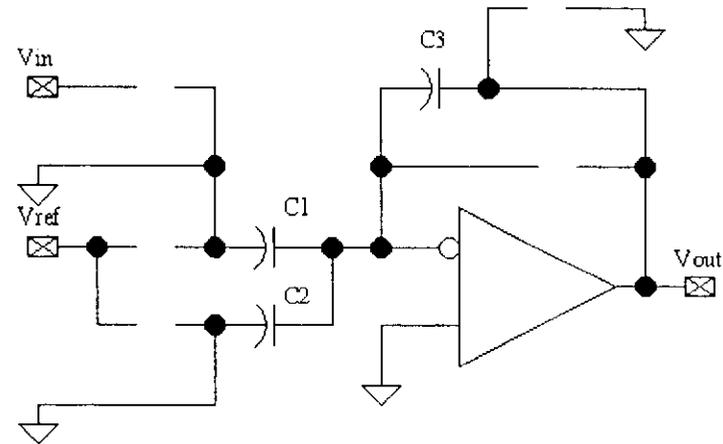
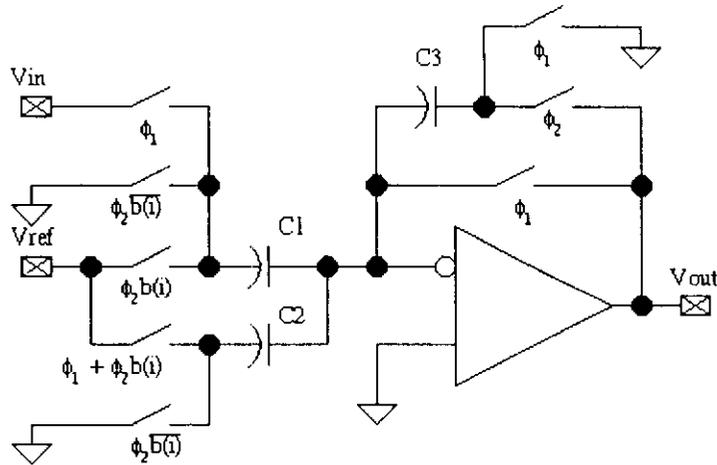


$$Q1 = C1 V_{in}$$

$$Q2 = C2 V_{ref}$$

$$Q3 = 0$$

$\phi_2 \quad b(i) = 0$



$$Q1' = 0$$

$$Q2' = 0$$

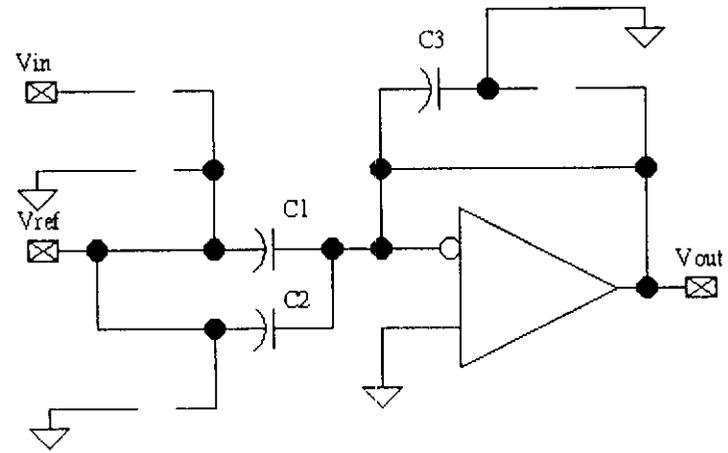
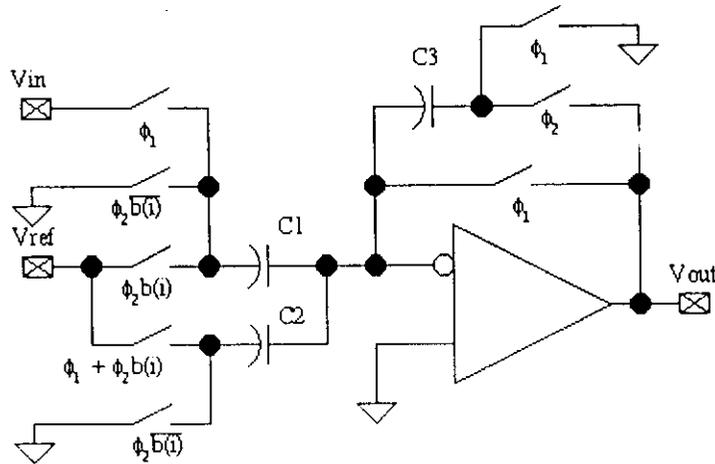
$$Q3' = C3 V_{out}$$

$$= Q1 + Q2$$

$$= C1 V_{in} + C2 V_{ref}$$

if $C1=C2=C3$ then **$V_{out} = V_{in} + V_{ref}$**

$\phi_2 \quad b(i) = 1$



$$Q1' = C1 Vref$$

$$Q2' = C2 Vref$$

$$Q3' = C3 Vout$$

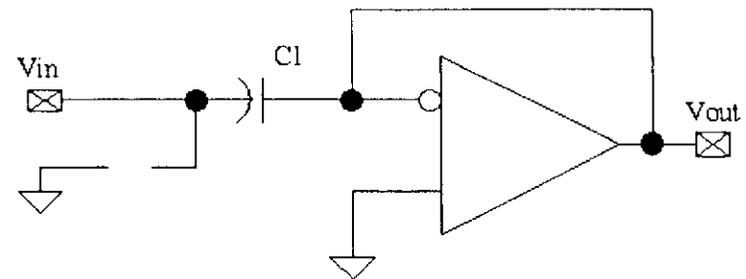
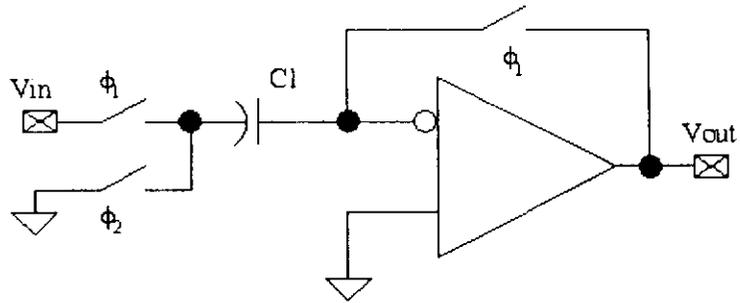
$$Q1' + Q2' + Q3' = Q1 + Q2$$

$$C1 Vref + \cancel{C2 Vref} + C3 Vout = C1 Vin + \cancel{C2 Vref}$$

if $C1=C3$ then

$$Vout = Vin - Vref$$

SC Comparator with Offset Cancellation (Autozero)



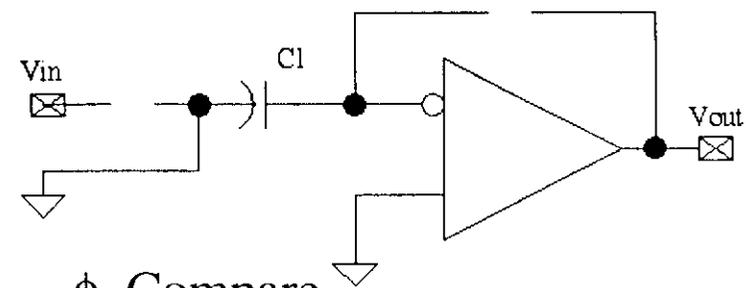
ϕ_1 Sample

$$V_{C1} = V_{in} - V_{off}$$

V_{off} = Offset Opamp
 A_v = Open Loop Gain

$$V_{out} = -A_v [-(V_{in} - V_{off}) - V_{off}]$$

$$= A_v V_{in}$$

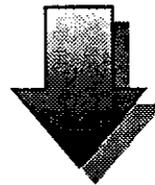


ϕ_2 Compare

Numerical Model and Simulation

- Amplifiers: Open Loop Gain, offset, GBW?
- Capacitors: Minimum Value, mismatching?
- Comparator: Maximum Offset?

The ADC has been fully described by a mathematical model and simulated with MATLAB to define the specification for each component to reach the required performance.

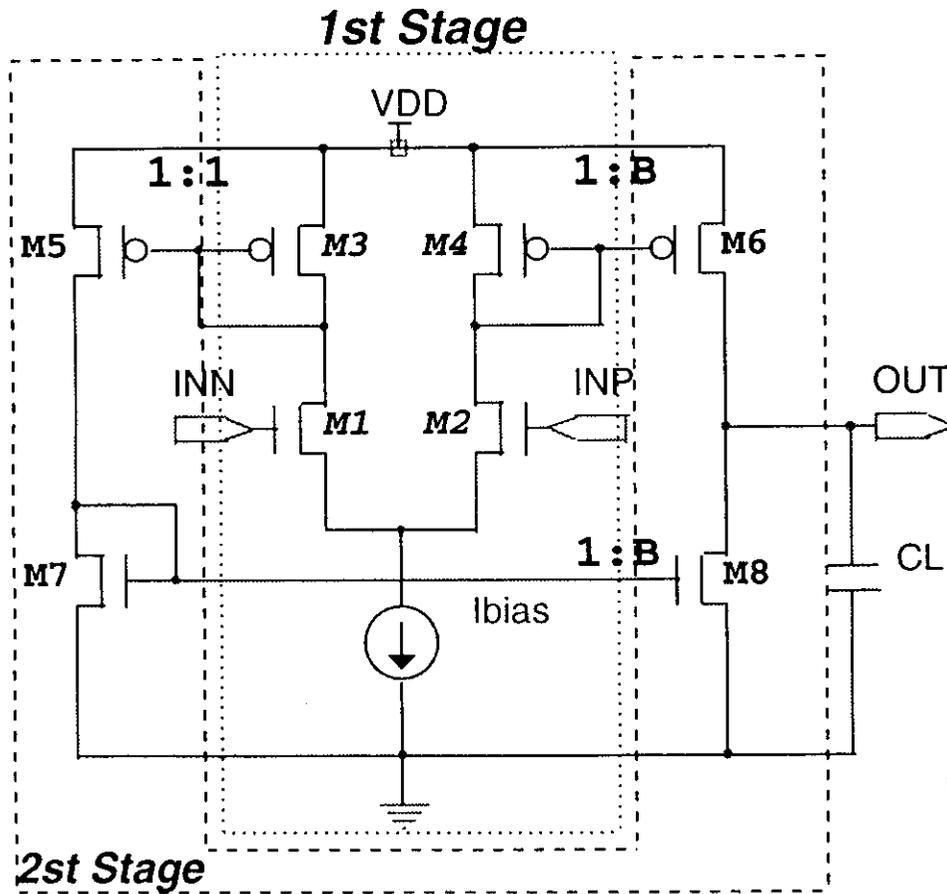


DESIGN SPECIFICATIONS

Analog and Digital Design

- Digital Part: very simple (phases generation, counters, combination logic).
- Analog Part: OTA with Very low power dissipation (Mosfet in weak inversion), switches array and capacitors array.

Operational Transconductance Amplifier



1st Stage

$M1=M2$ (weak inversion)
 g_m is geometry independent

$M3=M4$ (strong inversion)
 g_m is geometry dependent

2nd Stage

$M5=M7$ (strong inversion)
 $M6=M8$ (strong inversion)
 g_m is geometry dependent

$$g_m = B g_{m1}$$

weak

$$g_m = \frac{I_D}{nU_T}$$

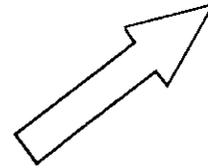
strong

$$g_m = \sqrt{2\mu C_{ox} \frac{W}{L} I_D}$$

M1 & M2 in weak inversion

$$GWB = \frac{g_m}{C_L} = \frac{g_{m(1)} B}{C_L}$$

$$I_D < \frac{W_{1(2)}}{L_{1(2)}} 5nA$$



$$GWB, C_L, B \text{ fixed} \Rightarrow g_{m1} \Rightarrow Id_1 = g_{m1} n U_T \Rightarrow \boxed{I_{bias}} = 2 Id_1$$

Gain 1st stage

$$A_{1st} = \frac{dV_{D2(1)}}{dV_{in}} = \frac{dV_{D2(1)}}{dI_{D2(1)}} \frac{dI_{D2(1)}}{dV_{in}}$$

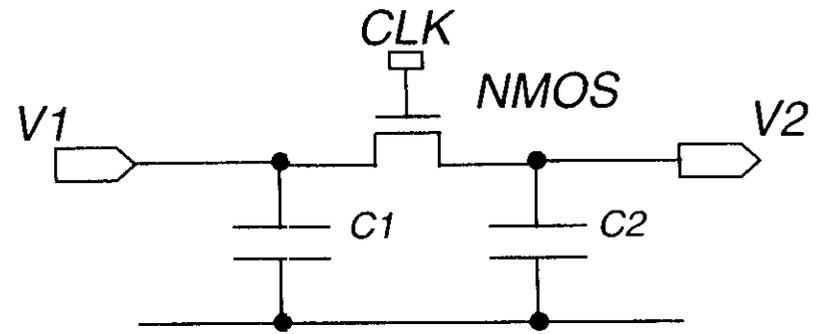
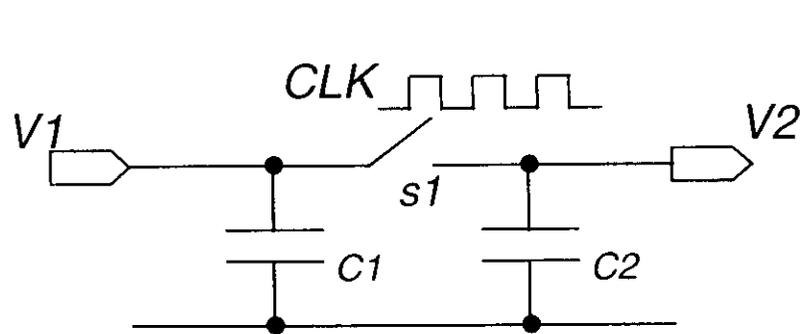
$$= \frac{g_{m1(2)}}{g_{m3(4)}} \Rightarrow g_{m3(4)} = \frac{g_{m1(2)}}{A_{1st}} \Rightarrow \frac{W_{3(4)}}{L_{3(4)}} = \frac{g_{m3(4)}^2}{2\mu C_{ox} I_D}$$

$$\frac{W_5}{L_5} = \frac{W_{3(4)}}{L_{3(4)}} \text{ and } \frac{W_6}{L_6} = B \frac{W_{3(4)}}{L_{3(4)}}$$

for symmetry

$$g_{m8} = g_{m6} = B g_{m3(4)} \Rightarrow \frac{W_8}{L_8} = \frac{g_{m8(6)}^2}{2\mu C_{ox} I_D} \text{ and } \frac{W_7}{L_7} = \frac{1}{B} \frac{W_8}{L_8}$$

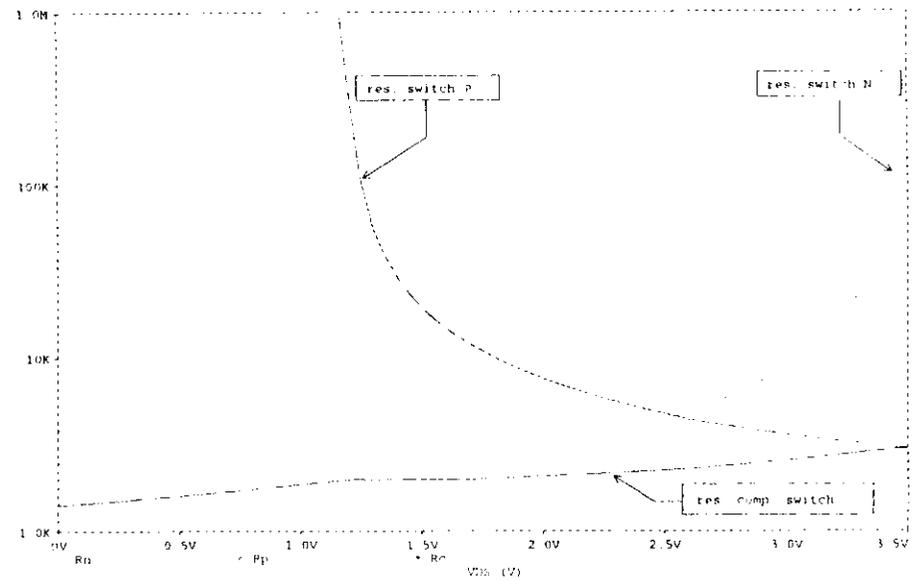
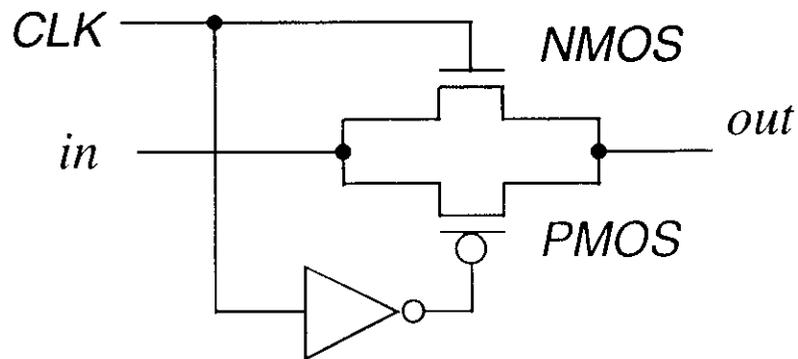
Switches



Problem 1: "On" Conductance.

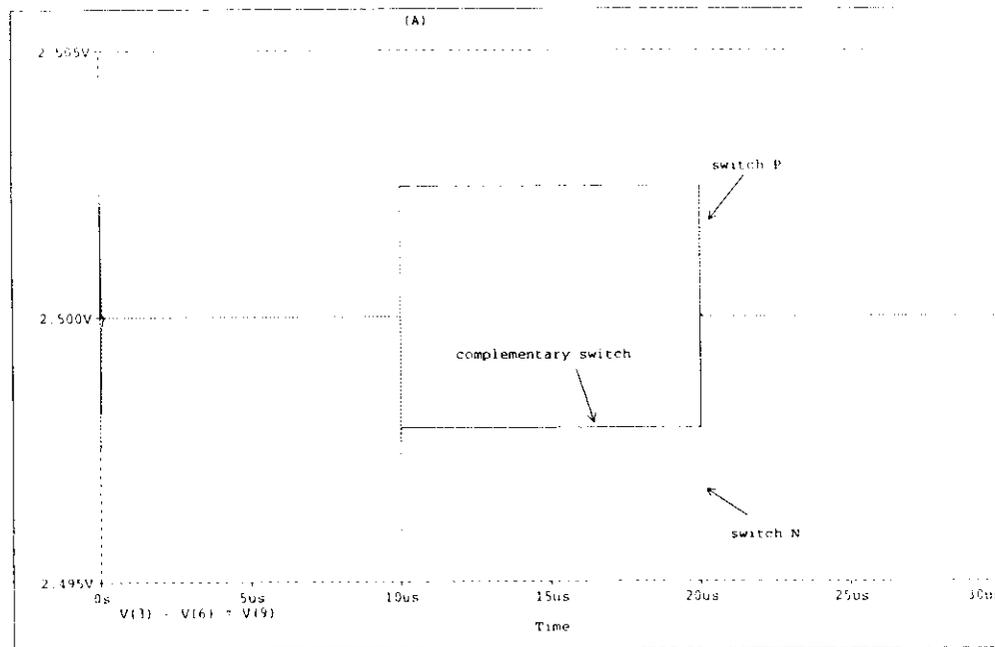
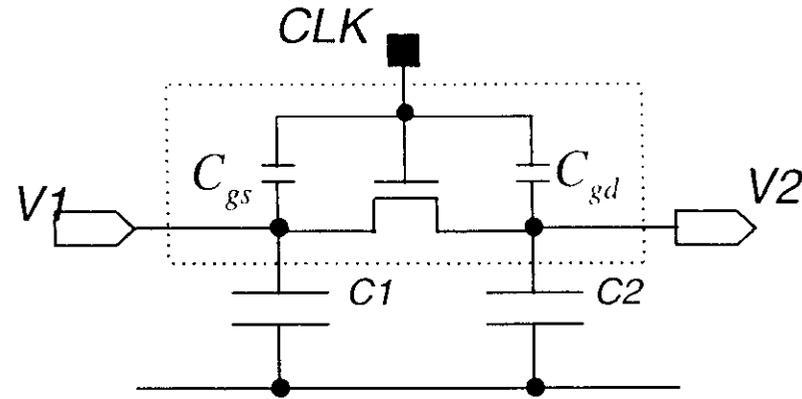
When the switch is turned on, the conductance depends on the difference between the input and the clock voltage level.

Solution 1: Complementary switches.

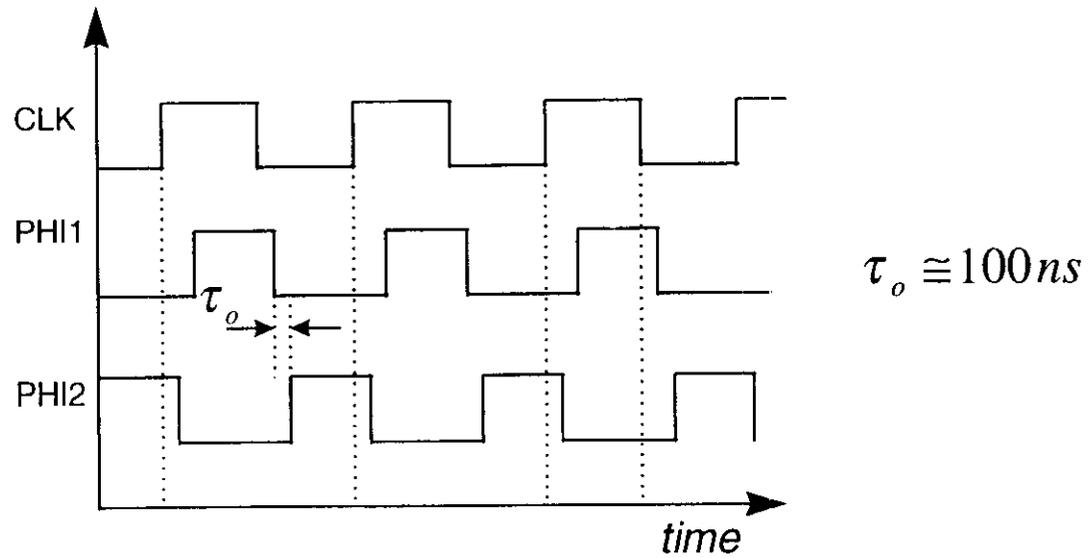
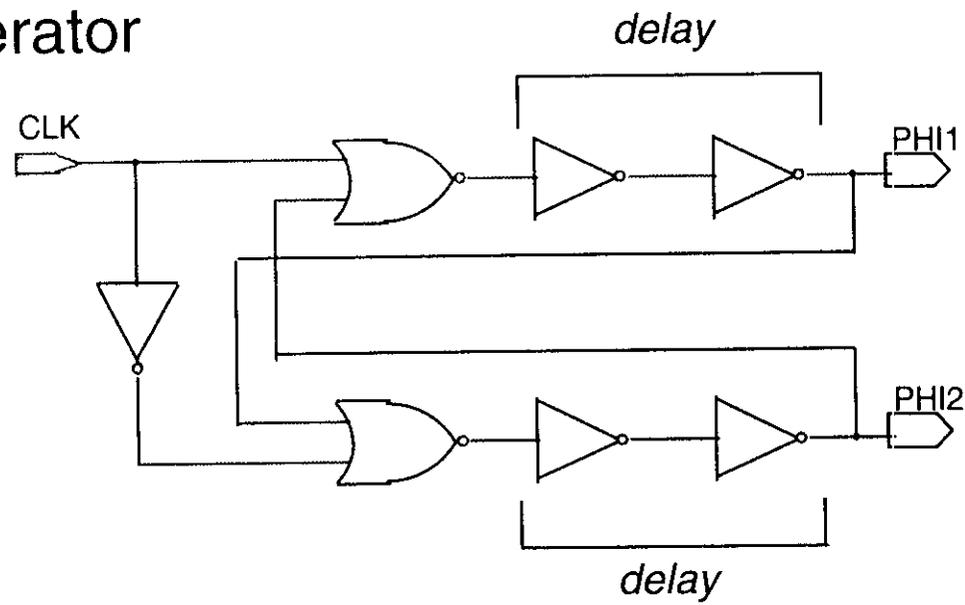


Problem 2: Clock Feedthrough.
 When the switch is turned off, a lot of charge is injected on capacitors (due to transistors channel charge and transistors parasitic capacitors).

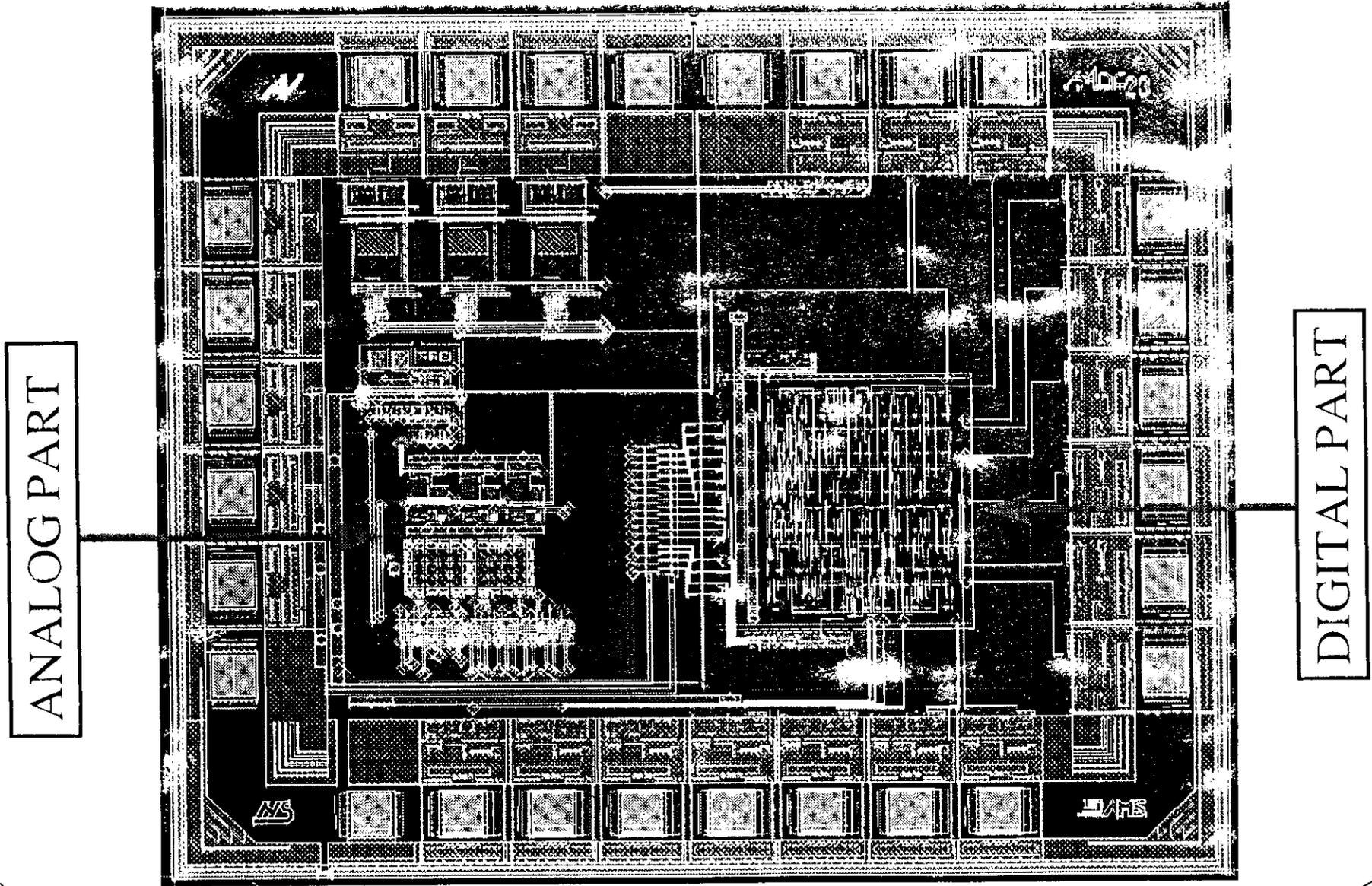
Solution 2: Partial Clock Feedthrough cancellation with complementary switch.



Phases Generator

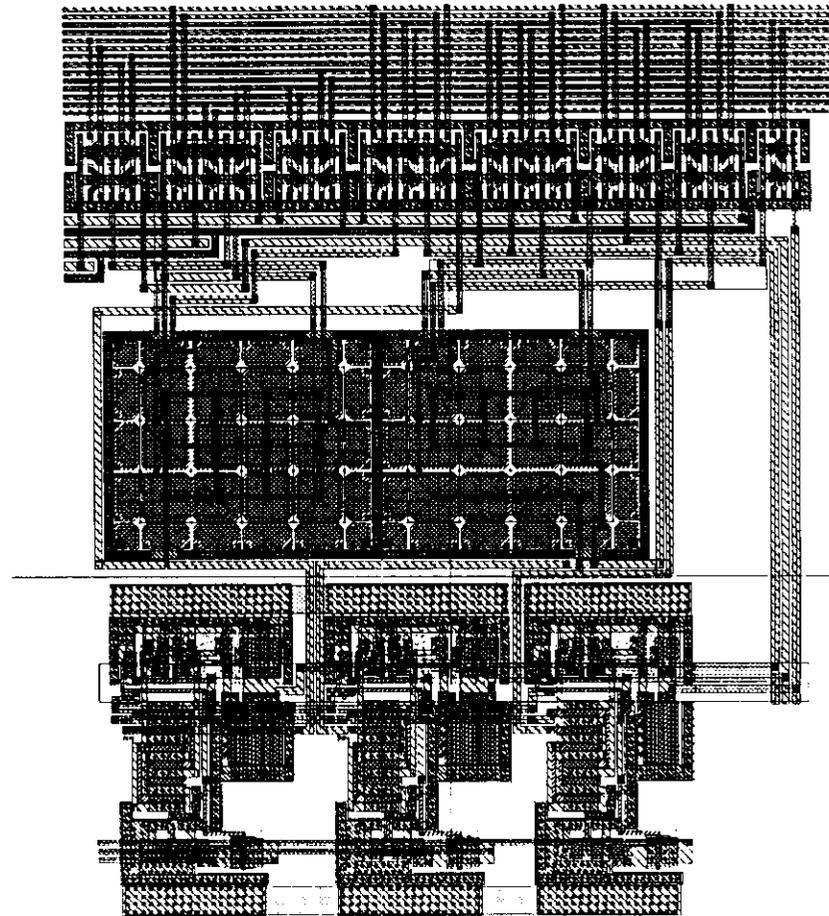
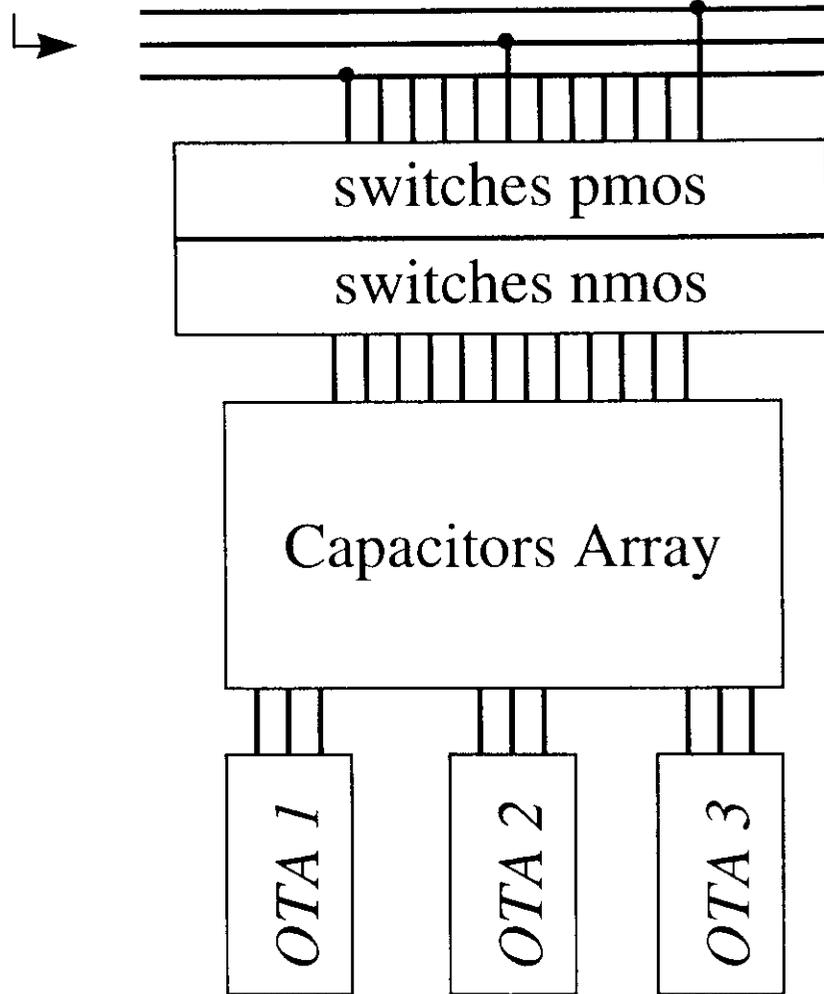


Layout



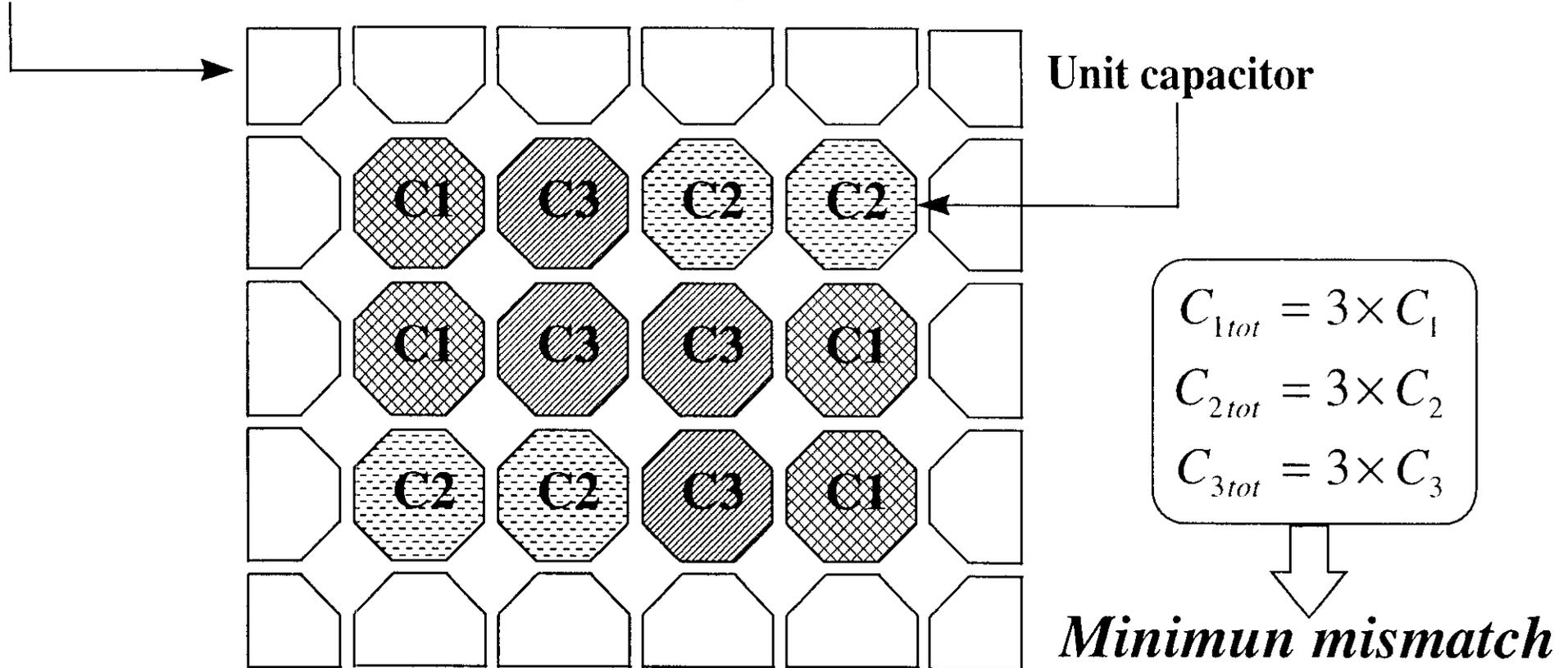
Layout Analog Part

phases lines



Capacitors matching techniques

Dummy capacitors: solve border effect problem.



- Exagonal shape of unit capacitors: Minimize geometry errors
- Barycentric structure: oxide thickness variation is mediate

Test Results

microADC

1	REF	GNDS	28
2	IN	RB	27
3	GNDA	IB	26
4	GNDD	T1	25
5	CTRL	T2	24
6	START	T3	23
7	CK	VDDA	22
8	SOUT	VDD	21
9	DRDY	PWDTS	20
10	SYNC	PWD	19
11	P7	P0	18
12	P6	P1	17
13	P5	P2	16
14	P4	P3	15

microADC

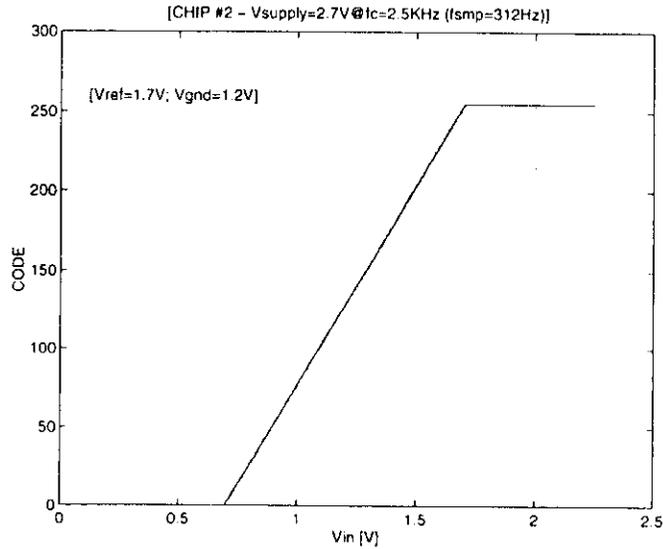
N° Pin (Analog pins)	NAME	Function
1	REF	Reference Voltage (V_{REF})
2	IN	Input Voltage
3	GNDA	Analog Ground
22	VDDA	Analog Voltage Supply
23	T1	Test Out (Comparator)
24	T2	Test Out (Ampli x2)
25	T3	Test Out (Sub / Add)
26	IB	Test I _{bias} (I _{bias} is the Bias Current)
27	RB	R for I _{bias}
28	GNDS	Signal Ground

N° Pin (Digital pins)	NAME	Function
4	GNDD	Digital Ground
5	CTRL	Control conversion type (ctrl=0 one shot, ctrl = 1 continuous sampling)
6	START	Start conversion
7	CK	Master Clock
8	SOUT	Serial Out
9	DRDY	Data ready
10	SYNC	Syncro out per (for SOUT)
11 - 18	P<7-0>	Parallel Out
19	PWD	Power down/ Logic Reset
20	PWDTS	Test Out Buffers Power down
21	VDD	Digital Voltage Supply

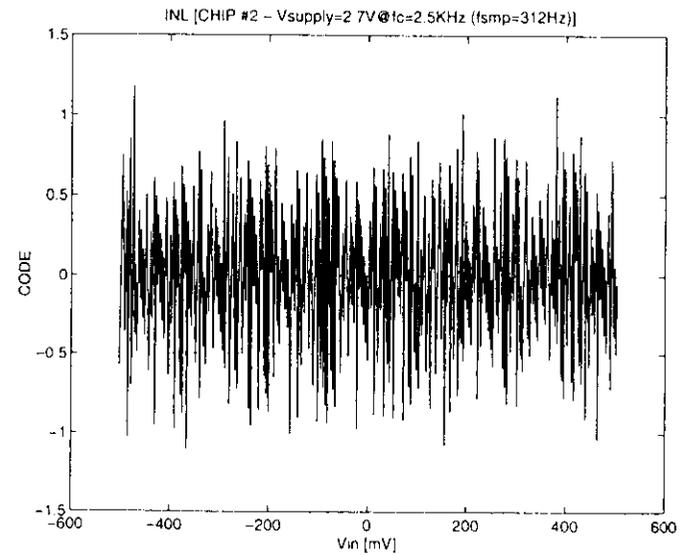
Test Results

	min	typ	max
Vsupply	2.0 V	2.7 V	3.3 V
V_{ref}		1.7 V	
V_{gnds}		1.2 V	
Range		$(V_{ref} - V_{gnds}) \div (V_{ref})$	
Isupply		1.5 μ A	2 μ A
N. bits		8	
Clock frequency		2.5 KHz	20 KHz
Sample frequency		0.312 KHz	2.5 KHz
INL		< 1 LSB	< 2 LSB
Gain error		1 LSB	< 1.5 LSB
Offset error		0.5 LSB	< 2.5 LSB

DC TESTS ($V_{supply} = 2.7V$, $temp=25 C$, $f_{clock}=2.5 KHz$ ($f_{sample} = 312Hz$))

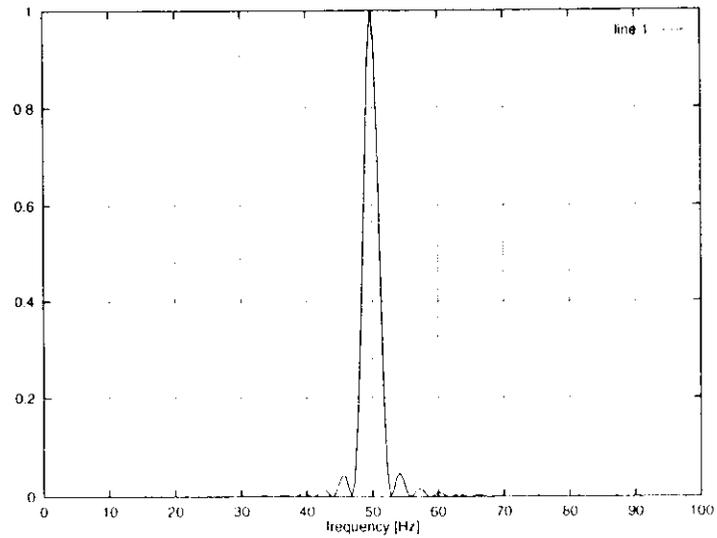
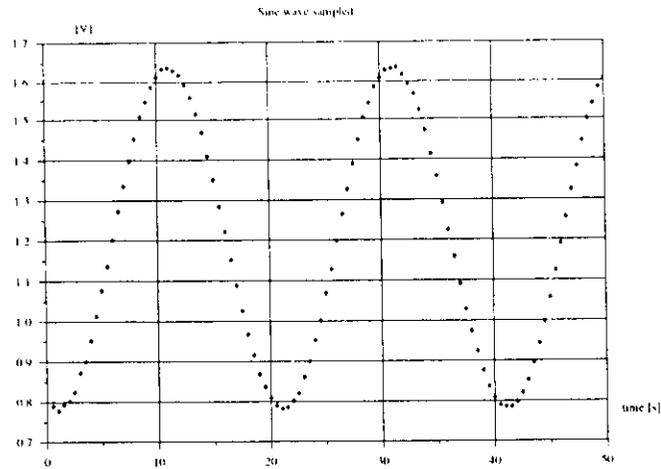


Vin VS CODE OUT

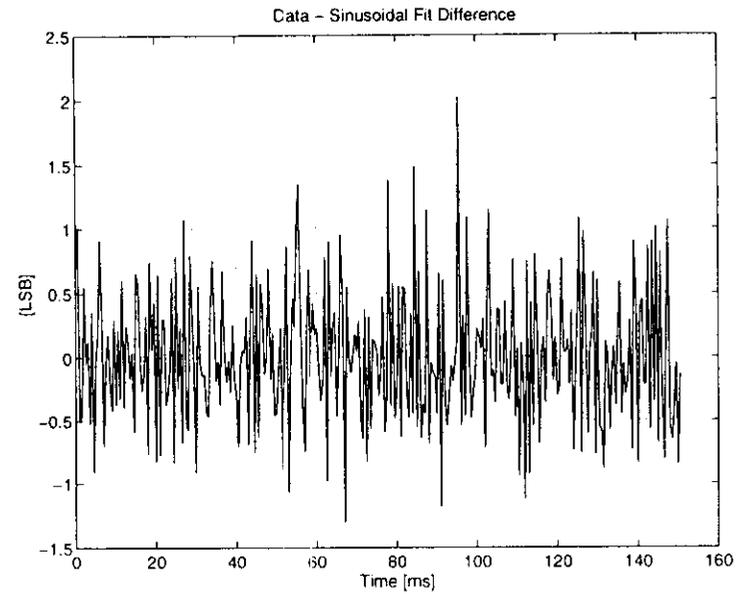


INL error

Dynamic Tests: Sine Wave Input

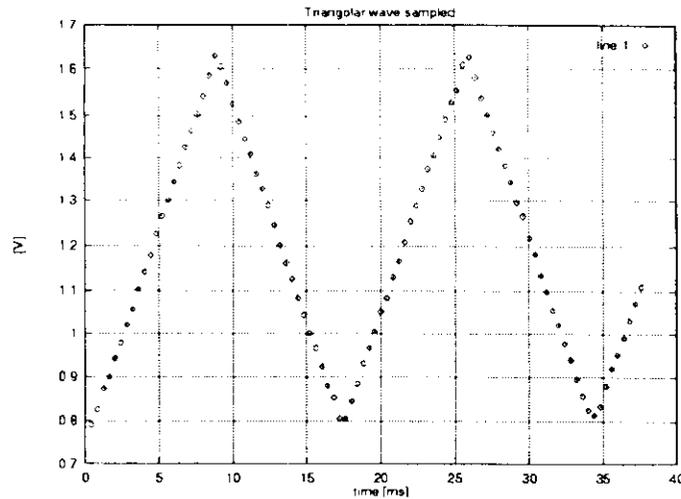


FFT OF SAMPLED DATA



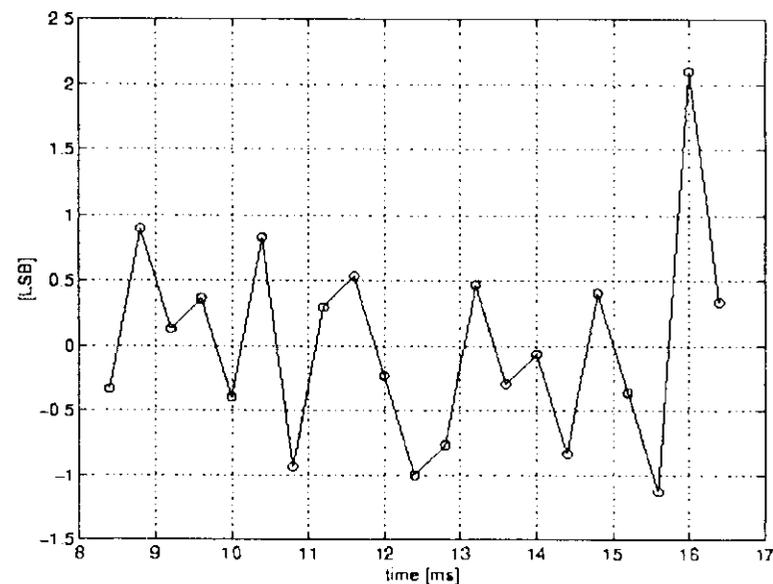
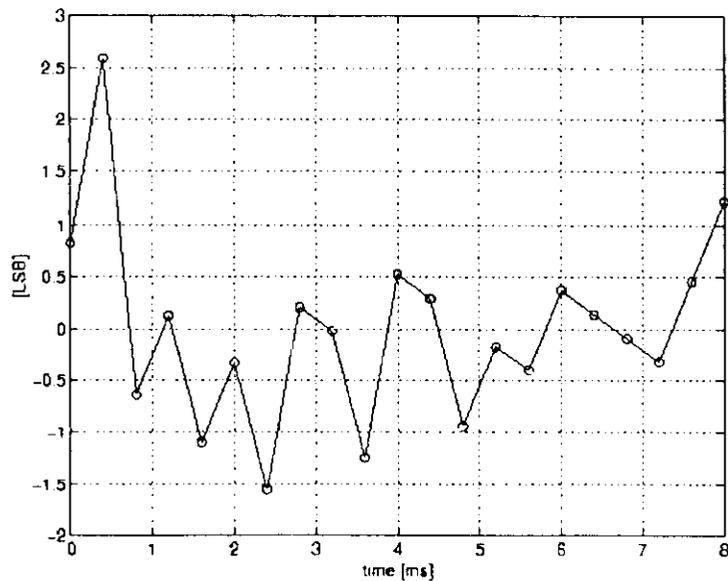
**SAMPLED DATA - SINUSOIDAL FIT
DIFFERENCE**

Dynamic Tests: Triangular Wave Input



input signal: Triangular wave	
Freq. =	50 Hz
Voff =	1.190 V
Vmax =	1.640 V
Vmin =	0.780 V
Vpp =	860 mV

ADC sets	
F_clock =	20 KHz
F_sample =	2.5 KHz
T_sample =	0.4 ms
Vsupply =	2.7 V
Temp =	25 °C



Sampled Data - Linear Fit Difference (Positive and Negative Slope)

APPLICATION INFORMATION

